Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/752,010	SEIKE, TOSHIMICHI
Examiner	Art Unit
Anh Q. Tran	2819

	SEARCHED				
Class	Subclass	Date	Examiner		
326	21	4/12/05	AT		

ראו	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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